

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	19	(user and scan) adj register	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/11 14:05
L2	3805	netlist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/11 14:05
L3	133	netlist and bist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/11 15:11
L4	114	netlist and bist and register	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/11 14:06
L5	16	netlist and bist and register and fpga	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/11 15:00
L6	0	scan same netlist same silicon	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/11 15:00
L7	0	((703/16.ccls) or (703/15.ccls) or (716/4.ccls) or (716/5.ccls)) and netlist and bist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/11 15:13
L8	0	((703/16.ccls) or (703/15.ccls) or (716/4.ccls) or (716/5.ccls)) and netlist and (self adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/11 15:13
S1	127	scan\$4 same test\$3 same FPGA	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/22 15:12

S2	77	test\$3 same (FPGA with scan\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/22 15:12
S3	0	netlist with syndrome	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/22 17:30
S4	0	BIST with syndrome	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/22 17:31
S5	0	FPGA with syndrome	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/22 17:30
S6	2	BIST same syndrome	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/22 17:31
S7	0	(FPGA and bist).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/18 22:33
S8	4	(FPGA and bist).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/18 22:32
S9	2	"6681354".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/18 22:32
S10	1176	(field adj programmable adj gate adj array).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/18 22:34
S11	1764	( FPGA (field adj programmable adj gate adj array)).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/18 22:34

S12	26	(built?in?self?test).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/18 22:35
S13	204	(BIST(built?in?self?test)).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/18 22:36
S14	1	(( FPGA (field adj programmable adj gate adj array)).ti.) and ((BIST(built?in?self?test)).ti.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/18 22:38
S15	11	FPGA and BIST and netlist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 09:39
S16	2	"6476636".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 09:39
S17	25	("5469003"   "5483178"   "5485103"   "5491353"   "5504439"   "5521529"   "5528176"   "5537057"   "5541530"   "5570041"   "5598109"   "5606266"   "5606267"   "5614840"   "5617042"   "5668771"   "5671432"   "5682107"   "5689195"   "5761099"   "5764583"   "5828229"   "5977793"   "6181162"   "6211697").PN.	USPAT	OR	ON	2004/06/21 09:56
S18	3	("5469003"   "5483178"   "5485103"   "5491353"   "5504439"   "5521529"   "5528176"   "5537057"   "5541530"   "5570041"   "5598109"   "5606266"   "5606267"   "5614840"   "5617042"   "5668771"   "5671432"   "5682107"   "5689195"   "5761099"   "5764583"   "5828229"   "5977793"   "6181162"   "6211697").PN. and scan	USPAT	OR	ON	2004/06/21 11:09

S19	0	((("5469003"   "5483178"   "5485103"   "5491353"   "5504439"   "5521529"   "5528176"   "5537057"   "5541530"   "5570041"   "5598109"   "5606266"   "5606267"   "5614840"   "5617042"   "5668771"   "5671432"   "5682107"   "5689195"   "5761099"   "5764583"   "5828229"   "5977793"   "6181162"   "6211697").PN.) and netlist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 09:57
S20	0	((("5469003"   "5483178"   "5485103"   "5491353"   "5504439"   "5521529"   "5528176"   "5537057"   "5541530"   "5570041"   "5598109"   "5606266"   "5606267"   "5614840"   "5617042"   "5668771"   "5671432"   "5682107"   "5689195"   "5761099"   "5764583"   "5828229"   "5977793"   "6181162"   "6211697").PN.) and bist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 09:57
S21	3125	netlist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 11:09
S22	105	netlist and (built?in?self?test or BIST)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 11:11
S23	12	netlist and (built?in?self?test or BIST) and FPGA	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 11:11
S24	9	netlist and (built?in?self?test or BIST) and FPGA and scan	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 11:11
S25	89	netlist and (built?in?self?test or BIST) and (field ?programmable?gate?array or FPGA) and scan	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 11:12

S26	9	netlist and (built?in?self?test or BIST) and (field?programmable?gate?array or FPGA) and scan	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 12:07
S27	0	netlist and (built?in?self?test or BIST) and (field?programmable?gate?array or FPGA) and scan and syndrome	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 12:10
S28	0	netlist and (built?in?self?test or BIST) and (field?programmable?gate?array or FPGA) and syndrome	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 12:08
S29	1	netlist and (built?in?self?test or BIST) and scan and syndrome	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 12:08
S30	0	(built?in?self?test or BIST) and (field?programmable?gate?array or FPGA) and scan and syndrome	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 12:09
S31	0	(field?programmable?gate?array or FPGA) and scan and syndrome and netlist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 12:10
S32	1	netlist and (built?in?self?test or BIST) and scan and syndrome	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 12:58
S33	1	netlist and (built?in?self?test or BIST) and syndrome	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 12:58
S34	20	netlist and ((built?in?self?test or BIST) with (generate generating generated generation))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 14:42
S35	47	(built?in?self?test or BIST) and (netlist with (generate generating generated generation))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 14:43

S36	4	(built?in?self?test or BIST) same (netlist with (generate generating generated generation))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 14:46
S37	1	syndrome and BIST and ((compare compared comparison comparing) with (expected adj value))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 16:51
S38	41	syndrome and ((compare compared comparison comparing) with (expected adj value))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 16:53
S39	8	BIST with netlist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 16:54